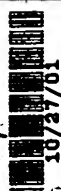


11011 U.S. PTO.  
10/046559



PATENT NUMBER and  
ISSUE DATE.

U.S. UTILITY Patent Application

APPL NUM 10046559	FILING DATE 10/27/2001	CLASS 324	SUBCLASS 158.1	GAU 2862	EXAMINER Jimmie - Nguyen
<b>**APPLICANTS:</b> Strom John; 2823					
<b>**CONTINUING DATA VERIFIED:</b> THIS APPLN CLAIMS BENEFIT OF 60/244,432 10/30/2000					
<b>** FOREIGN APPLICATIONS VERIFIED:</b>					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiner's initials				ATTORNEY DOCKET NO 11532-014001	
TITLE : Method and process of applying the analysis of scrub mark morphology and location to the evaluation and correction of semiconductor testing analysis, and manufacture					
<small>U.S. DEPT. OF COMM./PAT. &amp; TM-PTO-4361 (Rev. 12-94)</small>					

<b>NOTICE OF ALLOWANCE MAILED</b>		Assistant Examiner	<b>CLAIMS ALLOWED</b>	
			Total Claims	Print Claim for O.G.
<b>ISSUE FEE</b>		Primary Examiner	<b>DRAWING</b>	
Amount Due	Date Paid		Sheets Drwg.	Figs. Drwg.
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		PREPARED FOR ISSUE	Application Examiner	
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